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 Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

description

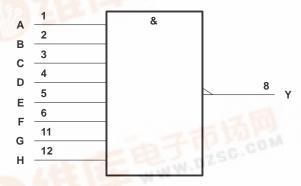
These devices contain a single 8-input NAND gate. They perform the Boolean functions $Y = \overline{A} \cdot \overline{B} \cdot \overline{C} + \overline{D} + \overline{E} + \overline{F} + \overline{G} + \overline{H}$ in positive logic.

The SN54F30 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74F30 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

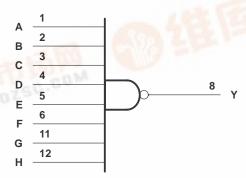
INPUTS A-H	OUTPUT Y
All inputs H	L
One or more inputs L	Н
olt www	N.DZSG

logic symbol†

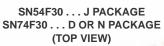


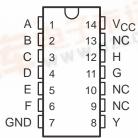
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)

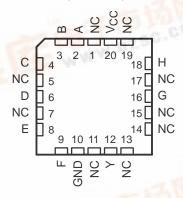


Pin numbers shown are for the D, J, and N packages.





SN54F30 . . . FK PACKAGE (TOP VIEW)



NC – No internal connection

SN54F30, SN74F30 8-INPUT POSITIVE-NAND GATES

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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	1.2 V to 7 V
Input current range	30 mA to 5 mA
Voltage range applied to any output in the high state	\dots -0.5 V to V _{CC}
Current into any output in the low state	40 mA
Operating free-air temperature range: SN54F30	. −55°C to 125°C
SN74F30	0°C to 70°C
Storage temperature range	. −65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input voltage ratings may be exceeded provided the input current ratings are observed.

recommended operating conditions

		SN54F30			SN74F30			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V _{IL}	Low-level input voltage			0.8			0.8	V
lik	Input clamp current			-18			-18	mA
IOH High-level output current				– 1			-1	mA
loL	Low-level output current			20			20	mA
TA	Operating free-air temperature	-55 125		0		70	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS		,	SN54F30			SN74F30		
			MIN	TYP [‡]	MAX	MIN	TYP [‡]	MAX	UNIT
VIK	V _{CC} = 4.5 V,	$I_{I} = -18 \text{ mA}$			-1.2			-1.2	V
Vou	$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -1 \text{ mA}$	2.5	3.4		2.5	3.4		V
VOH	$V_{CC} = 4.75 \text{ V},$	$I_{OH} = -1 \text{ mA}$				2.7			
V_{OL}	$V_{CC} = 4.5 \text{ V},$	$I_{OL} = 20 \text{ mA}$		0.3	0.5		0.3	0.5	V
IĮ	$V_{CC} = 5.5 \text{ V},$	V _I = 7 V			0.1			0.1	mA
lіН	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ
I _{IL}	V _{CC} = 5.5 V,	$V_{I} = 0.5 V$			- 0.6			- 0.6	mA
l _{OS} §	$V_{CC} = 5.5 \text{ V},$	V _O = 0	-60		-150	-60		-150	mA
Iссн	V _{CC} = 5.5 V,	V _I = 0		0.7	1.5		0.7	1.5	mA
ICCL	V _{CC} = 5.5 V,	V _I = 4.5 V		2.2	4		2.2	4	mA

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.



[§] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

SN54F30, SN74F30 8-INPUT POSITIVE-NAND GATES

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switching characteristics (see Note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	T 25°C		F, Ω,	C _L R _L	= 50 pF = 500 Ω = MIN t			UNIT
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	
t _{PLH}	A thru H		1	3.1	5	1	6	1	5.5	ns
t _{PHL}		ı	1	2.6	4.5	1	6	1	5	115

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 2: Load circuits and waveforms are shown in Section 1.

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